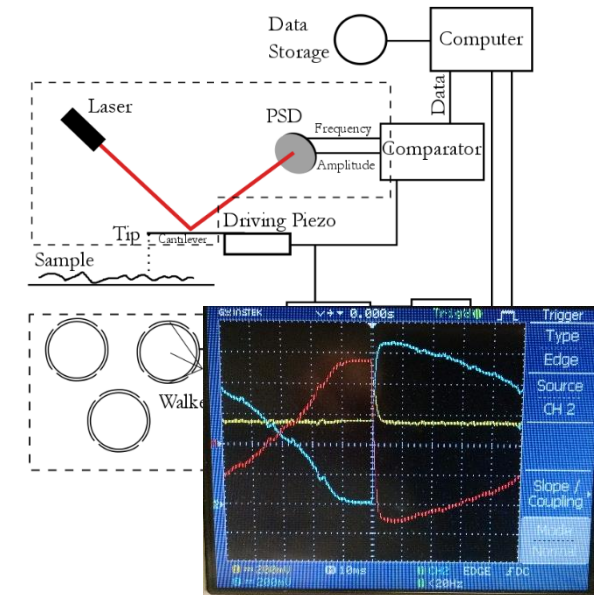
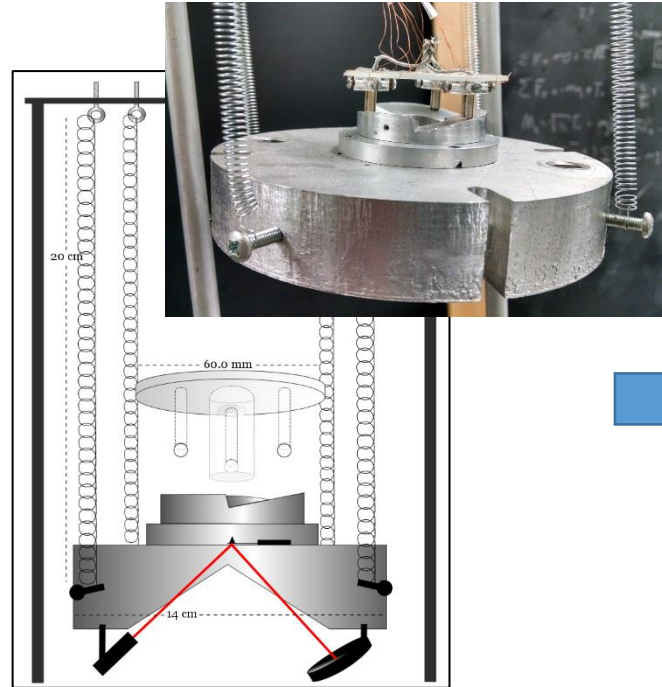
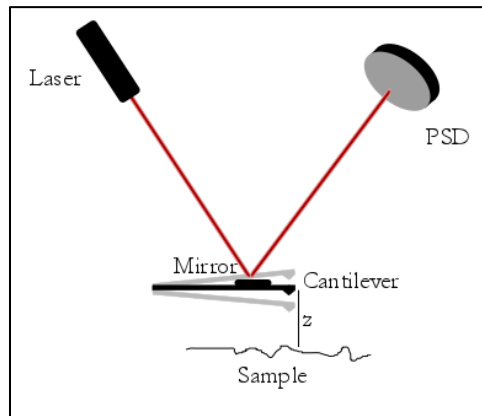


Design and Construction of An Atomic Force Microscope

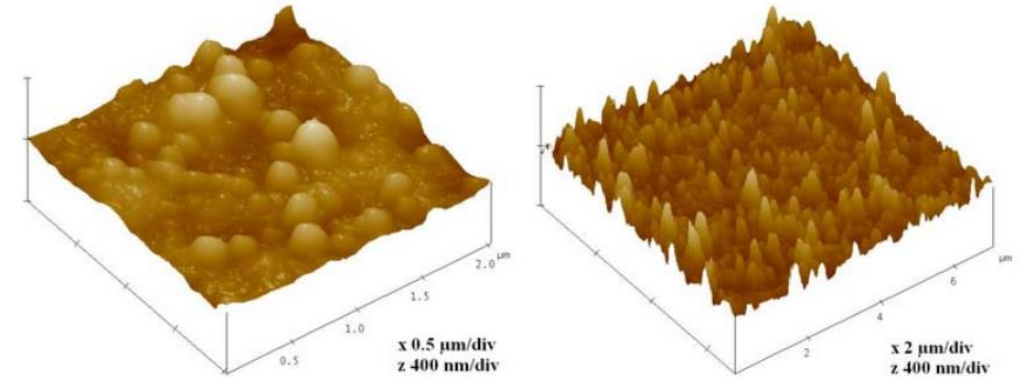


Outline



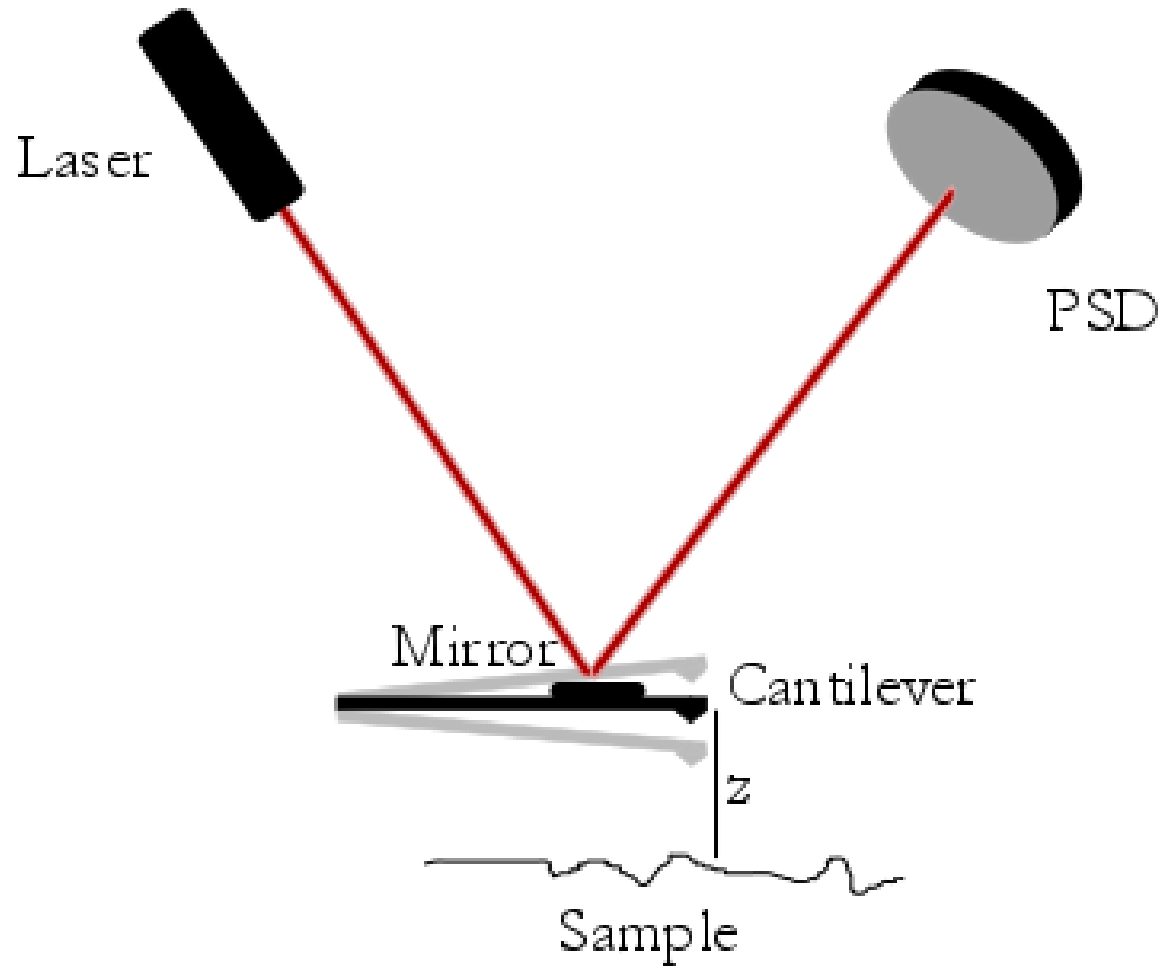
Motivation

- Directly observe structures on atomic scale
- Characterize thin films



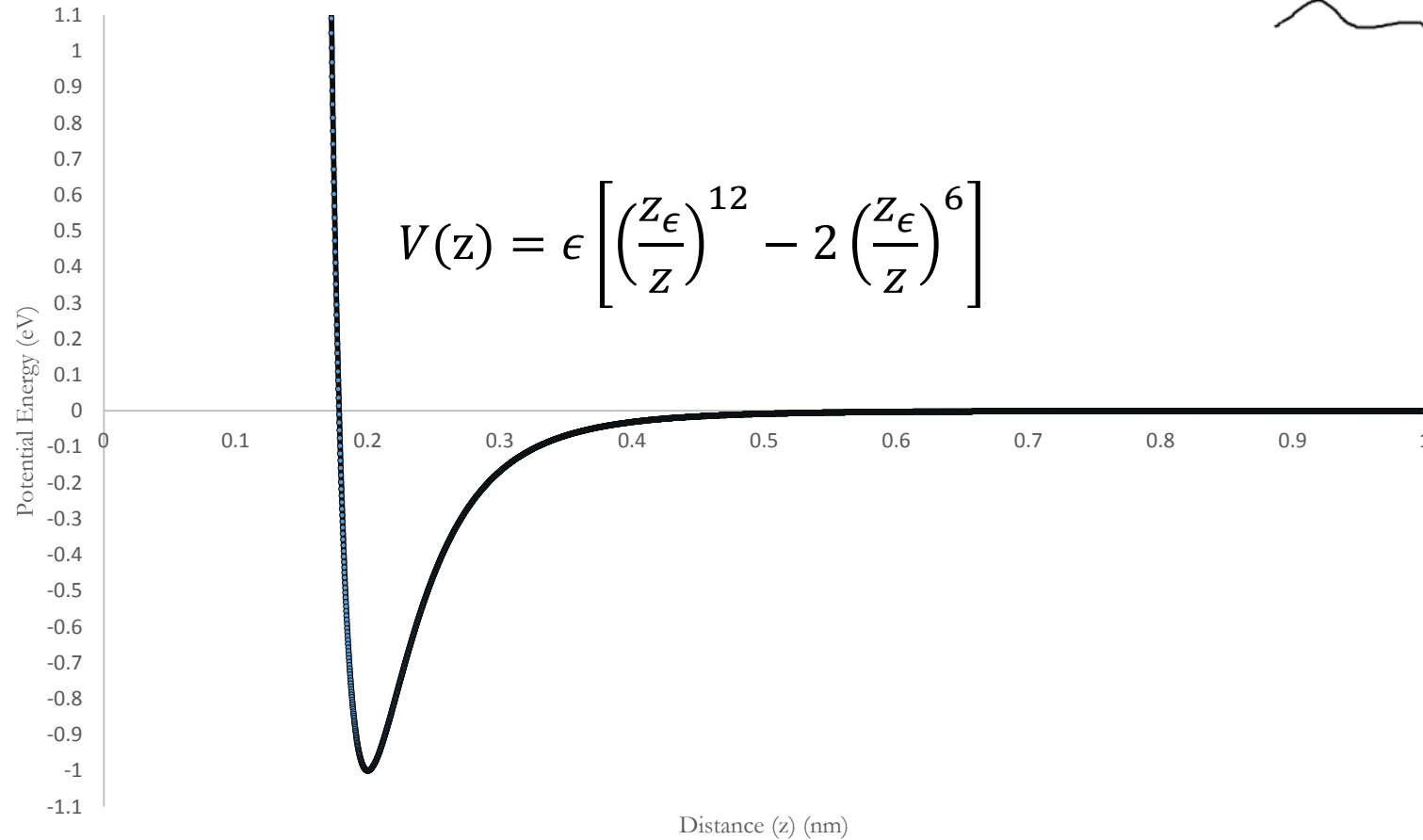
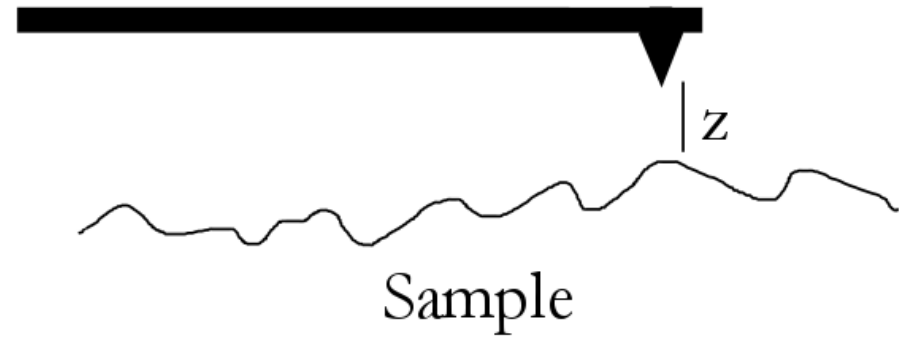
Burducea, I., Ionescu, C., Straticiuc, M., Craciun, L. S., Racolta, P. M., & Jipa, A. (2013). CHARACTERIZATION OF INDIUM NITRIDE AND ZINC OXIDE THIN FILMS BY AFM AND RBS. ROMANIAN JOURNAL OF PHYSICS, 58(3-4), 345-353.

Operation



- Static Mode
- Dynamic (Tapping) Mode

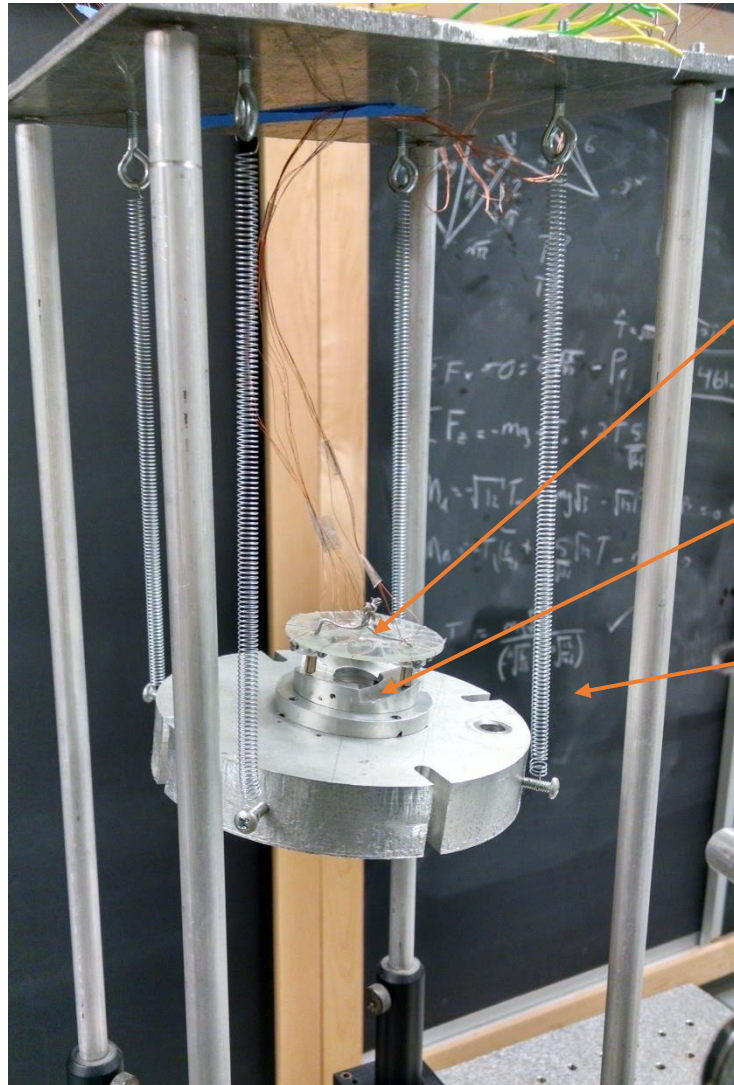
Tip-Sample Interaction



$$\ddot{z} + \frac{\omega_0}{Q} \dot{z} + \omega_0^2 z = A \omega_0^2 \cos \omega t$$

$$\frac{\Delta \omega}{\omega_0} \approx -\frac{1}{2k} \frac{\partial F}{\partial z}$$

Overall Design

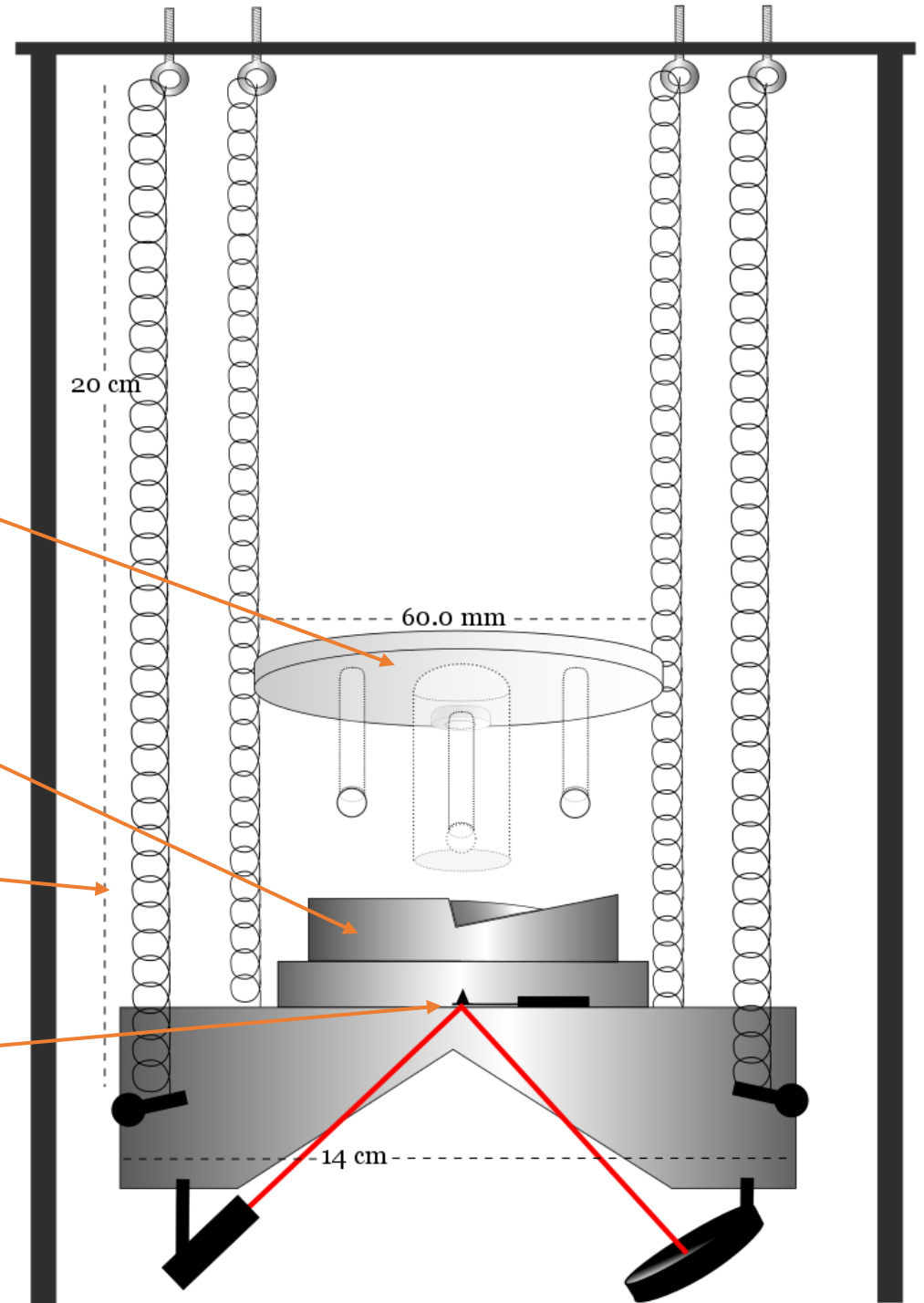


"Johnny Walker"

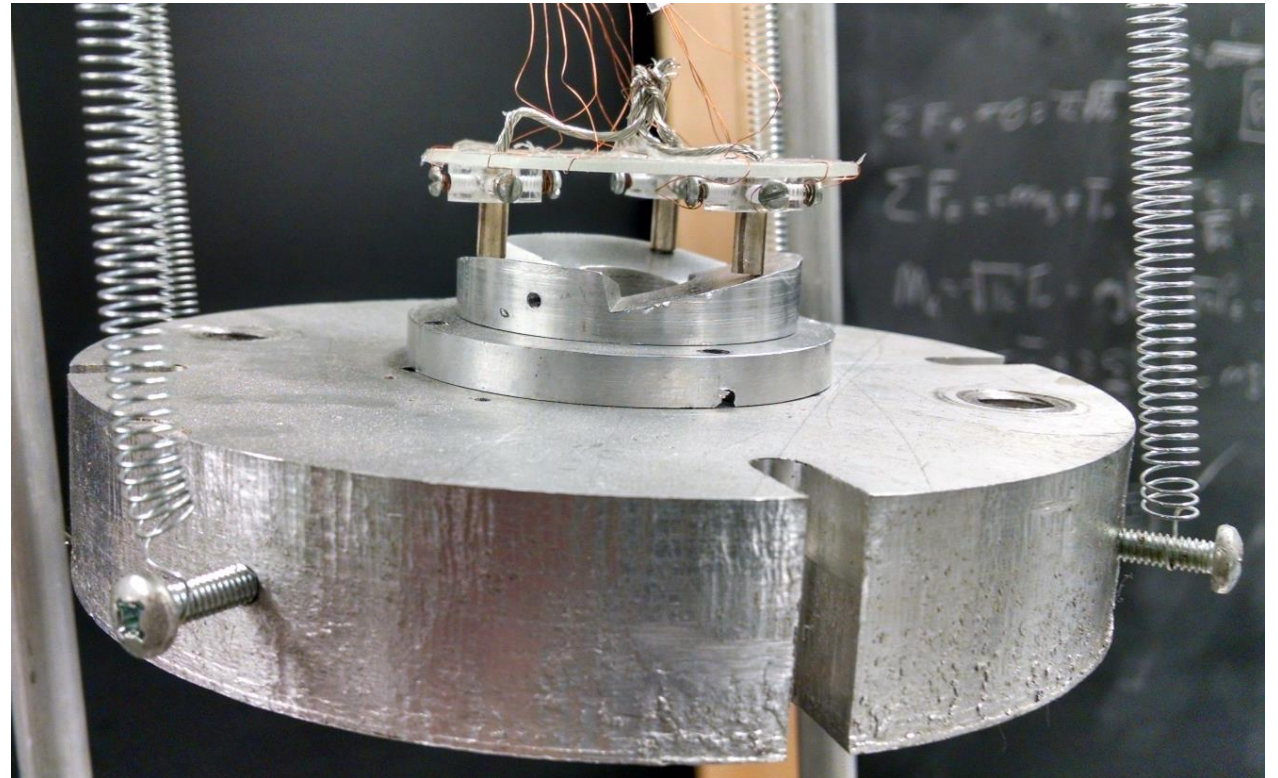
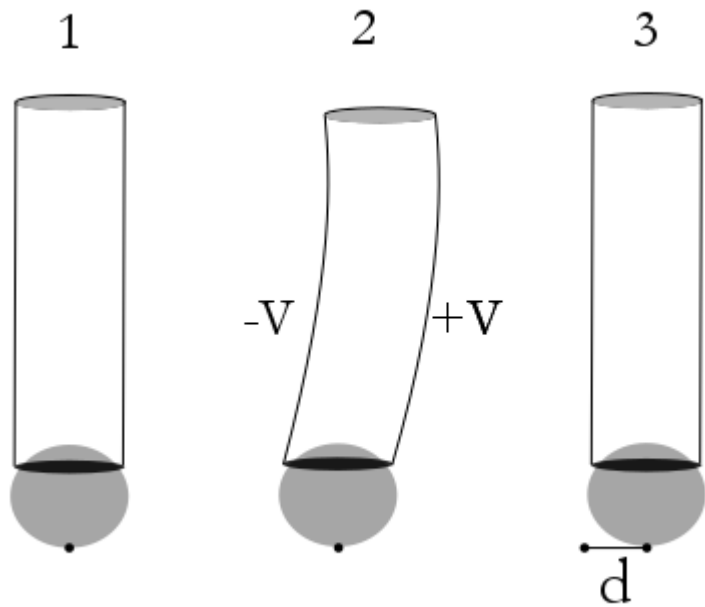
Ramp

Springs

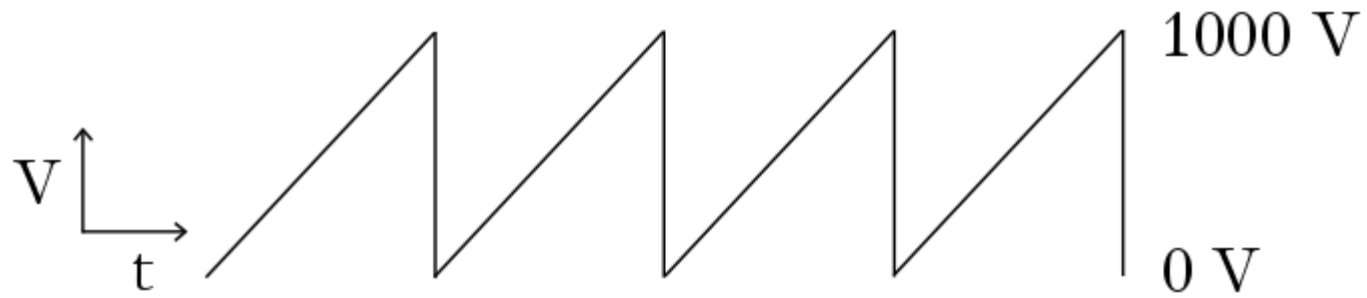
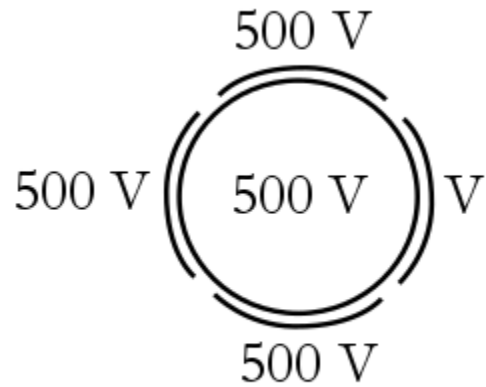
Cantilever



“Johnny Walker”



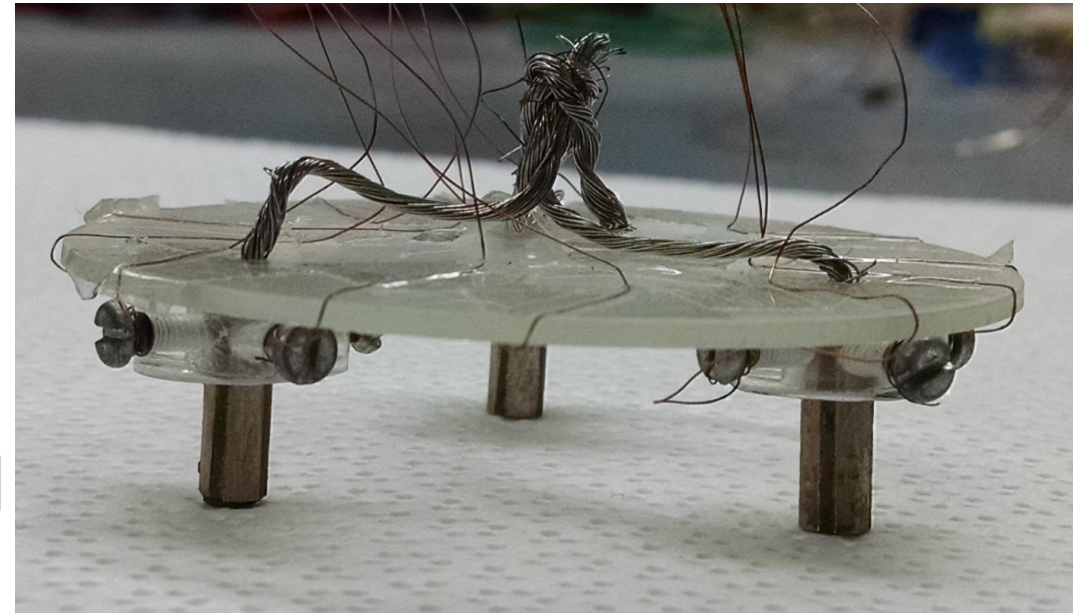
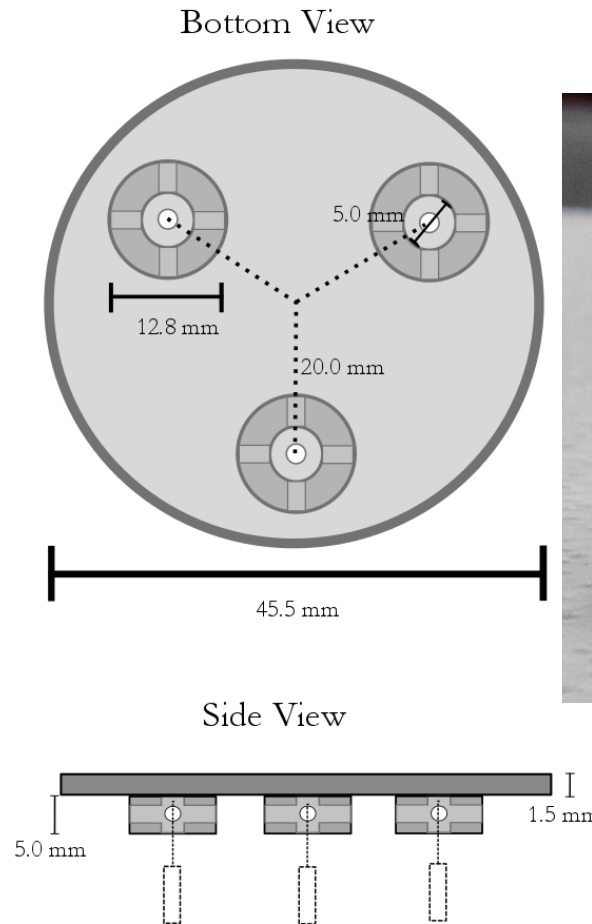
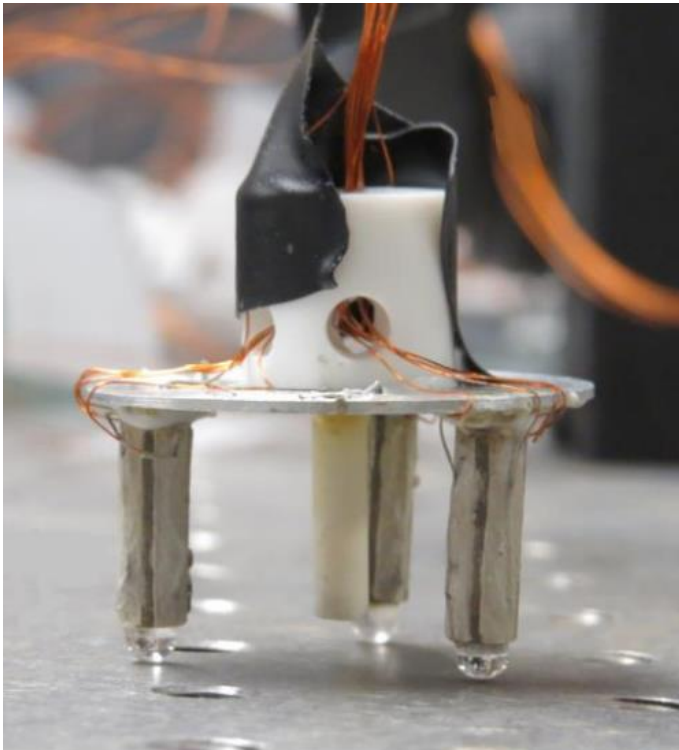
Walker Cont.



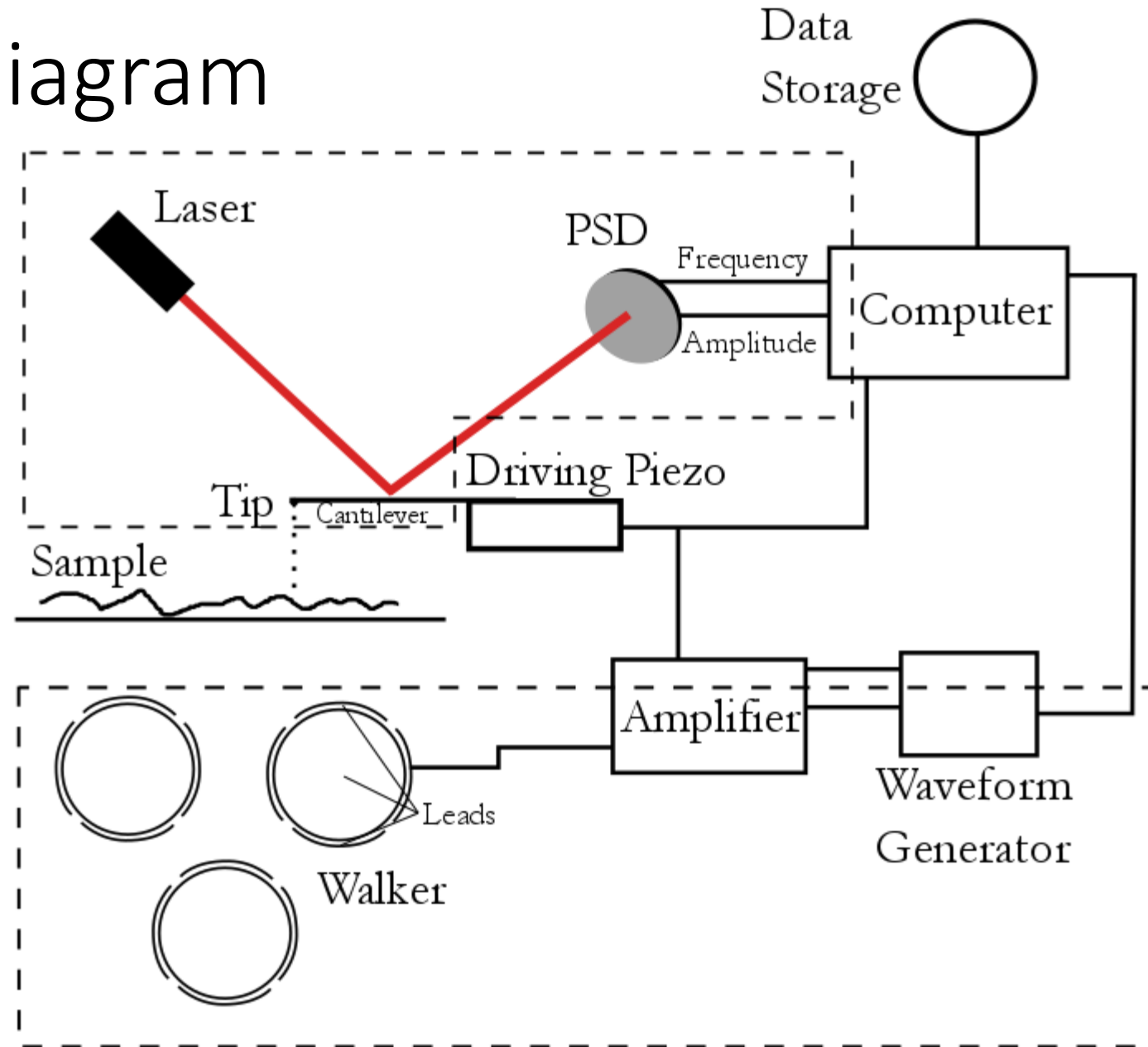
Walker Progress

New Design:

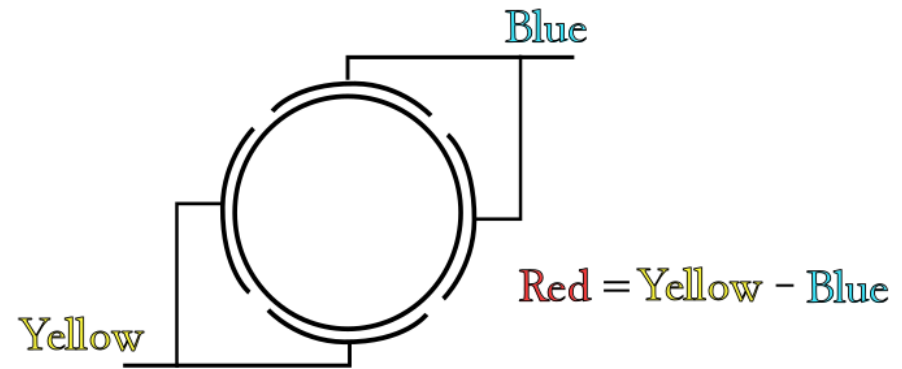
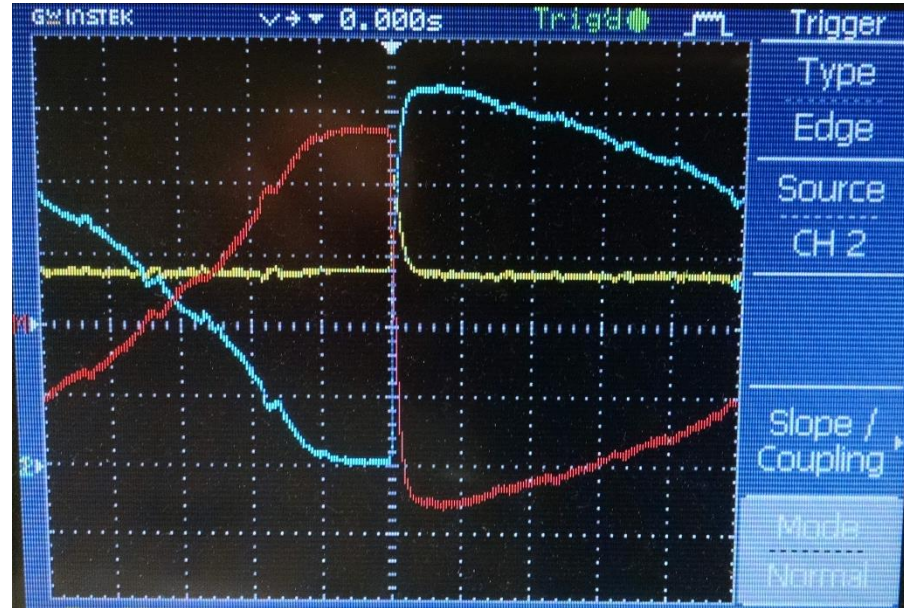
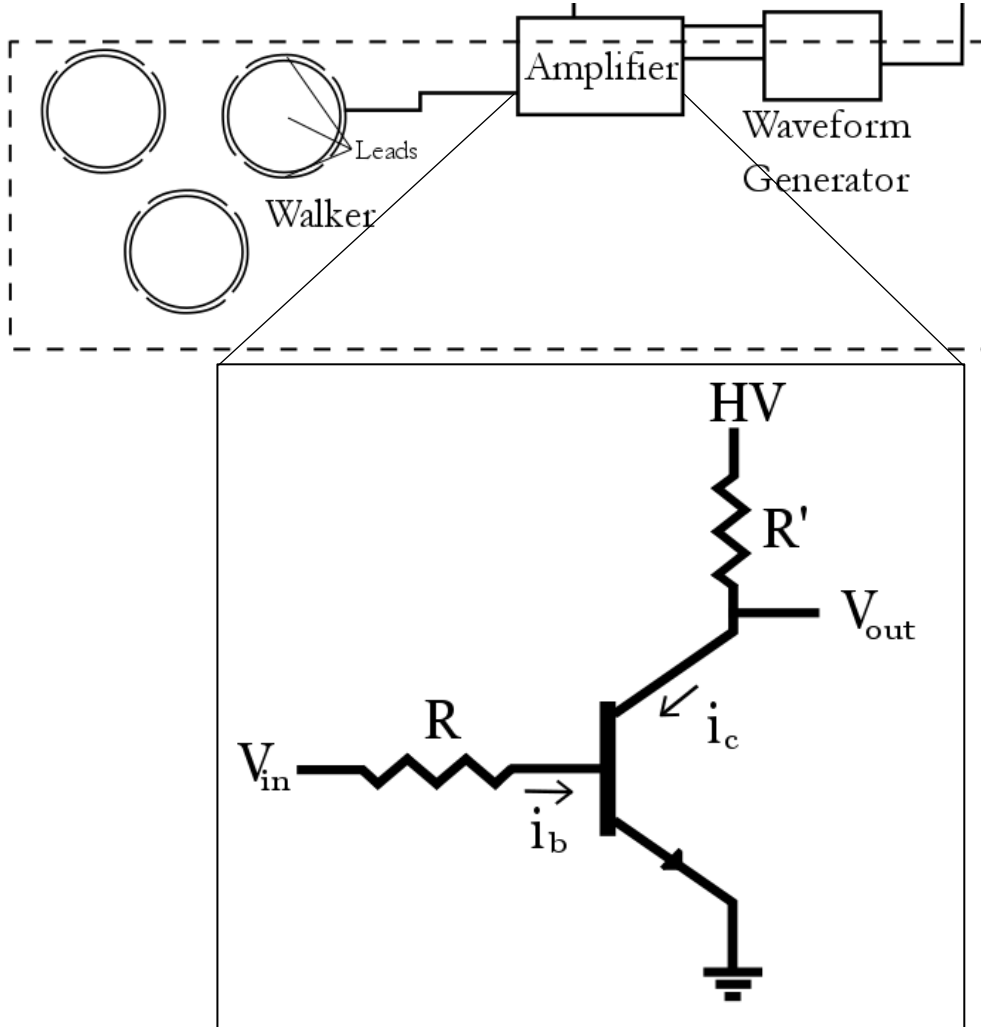
Old Design:



Block Diagram



Control Circuit Progress



In The Future

- Improve walker design
- Drive cantilever and add feedback from PSD

